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Radiation damage tests on silicon pad diodes with heavy ions at CERN IRRAD & CHARM facilities

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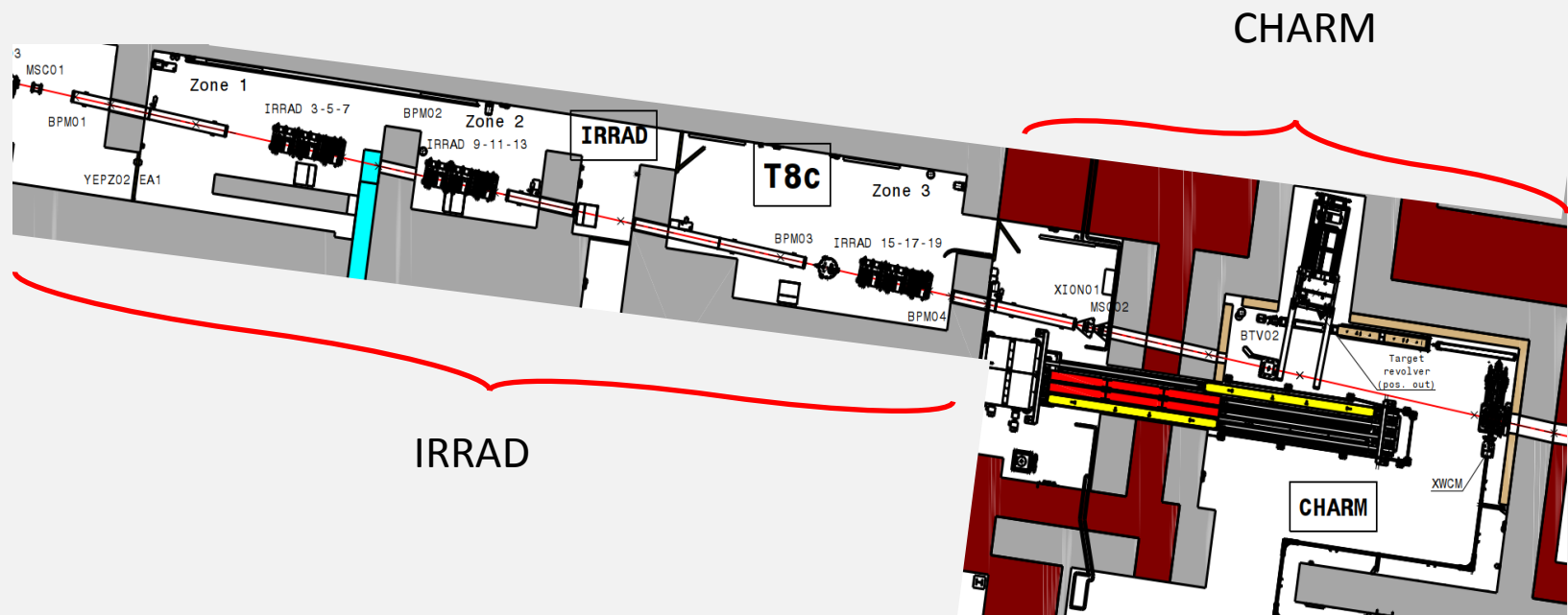


1. Heavy ions at CERN PS East Area.
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1. Heavy ions at CERN PS East Area

Motivation

- Radiation Hardness tests of Space Electronics Components (CHARM).
- High energy ions (few GeV/n range)
 - Representative of the Galactic Cosmic Ray spectrum (peak fluxes at ~ 1 GeV/n).
 - Highly penetrating.
 - \sim Constant Linear energy Transfer over the device under test volume.
- Characterize and propose IRRAD as a test area for EP heavy ion experiments (ALICE, NA61, etc.)
- 1st run in 12/2017 (Xenon ions) and 2nd run currently ongoing (Lead ions).



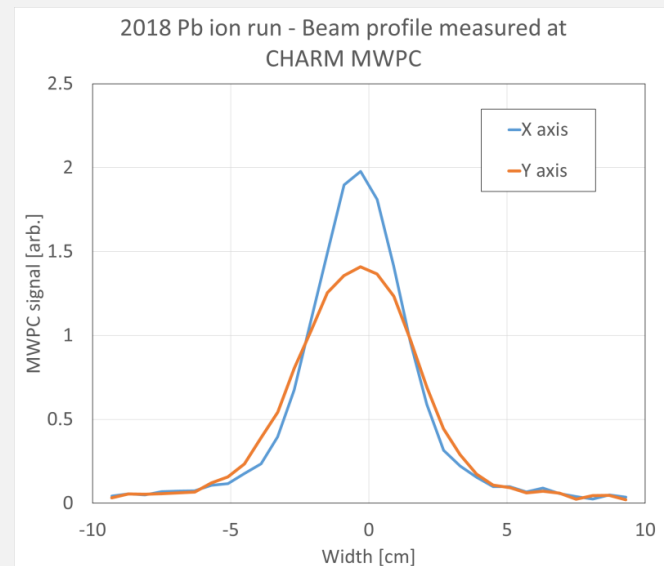
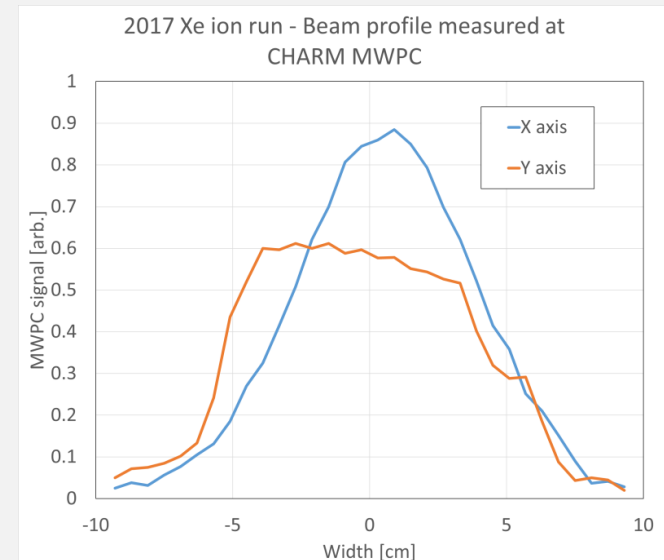
2017 and 2018 ion beams



	2017	2018
Element	Xenon (Xe)	Lead (Pb)
Charge state in the PS accelerator	39+	54+
Charge state after extraction *	54	82
Energy per nucleon	6.3 GeV/n	5.9 GeV/n
#nucleons	130	208
Ion energy	820 GeV	1222 GeV
Spill duration	~300 ms	
Ions/spill**	~2.8e8	1.3e9

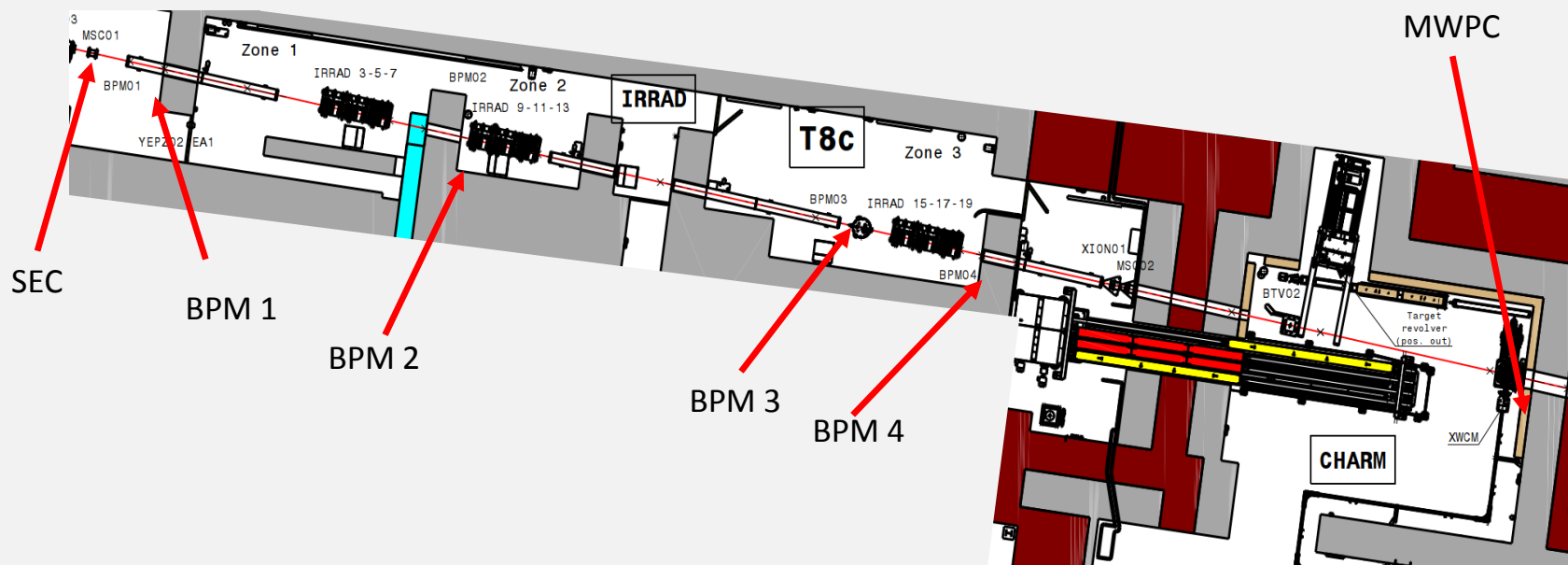
*ions are assumed to become fully stripped during the extraction.

**From beam instrumentation calibration (see next slide)



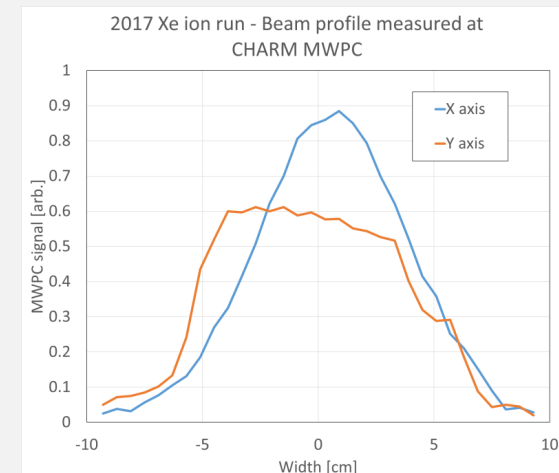
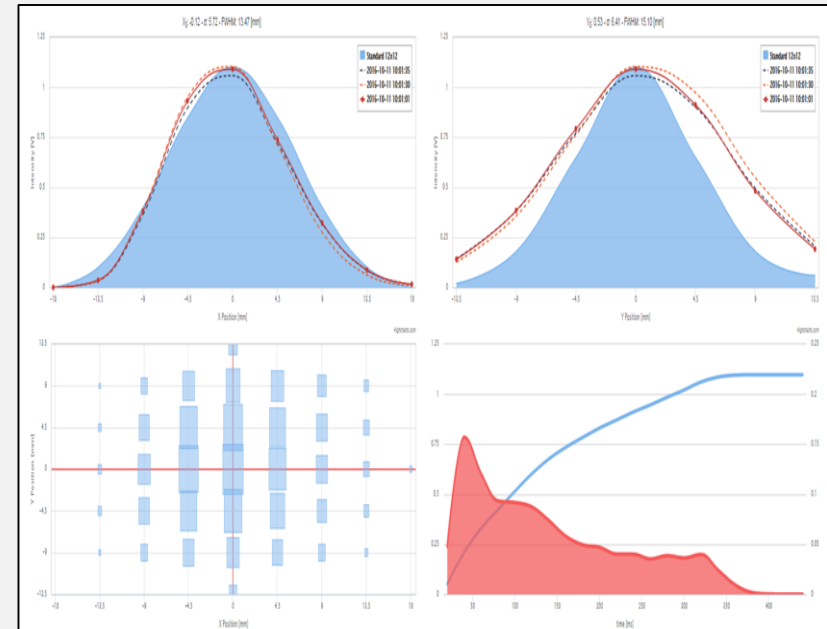
Beam instrumentation

- The IRRAD beam intensity is usually measured with a Secondary Emission Chamber (SEC), upstream of the facility.
 - Calibrated for ions against a Beam Current Transformer (BCT) measurement in a fast extraction run (~600 ns spills).
 - **Assumption:** the SEC response is maintained from fast to slow extraction.
- Beam profile is monitored using the IRRAD and CHARM instrumentation, normally dedicated to the proton beam.
 - Beam Profile Monitors (BPM) in IRRAD.
 - X-Y Multi Wire Proportional Chamber (MWPC) in CHARM.



Beam instrumentation

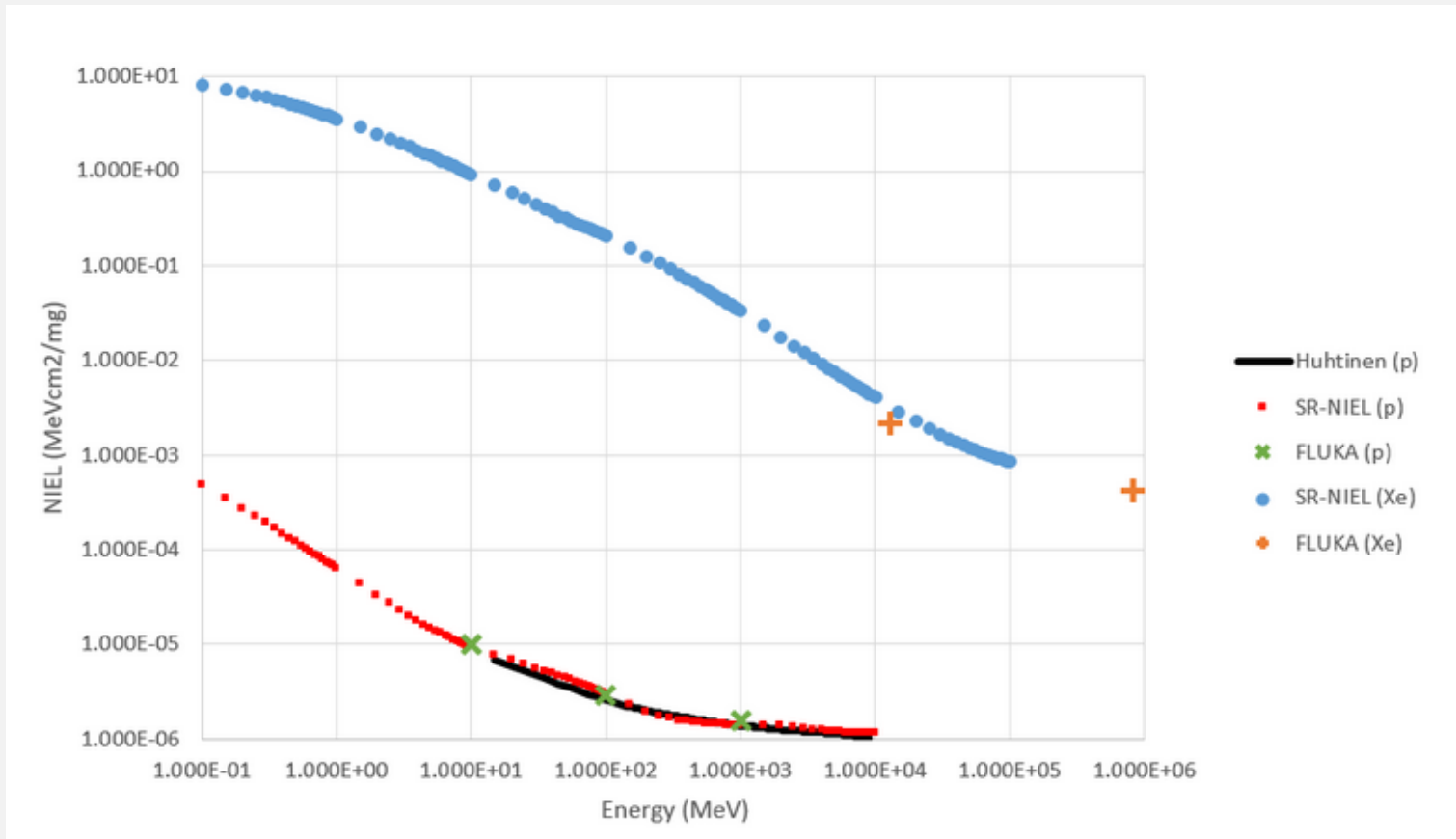
- The **BPM** are patterned copper foils working on the same physical principle of the SEC.
 - Patterned with 40 pads of equal size and 4.5 mm pitch (x and y).
 - Covering an area of 31 x 22 mm².
 - Linear response up to the highest intensities with the typical proton beam in IRRAD.
- **MWPC:**
 - 32 wires in each axis with 6 mm pitch.
 - 18.6 x 18.6 cm² coverage.
 - Expected to saturate with the ion beam.



2.NIEL study on silicon pad detectors

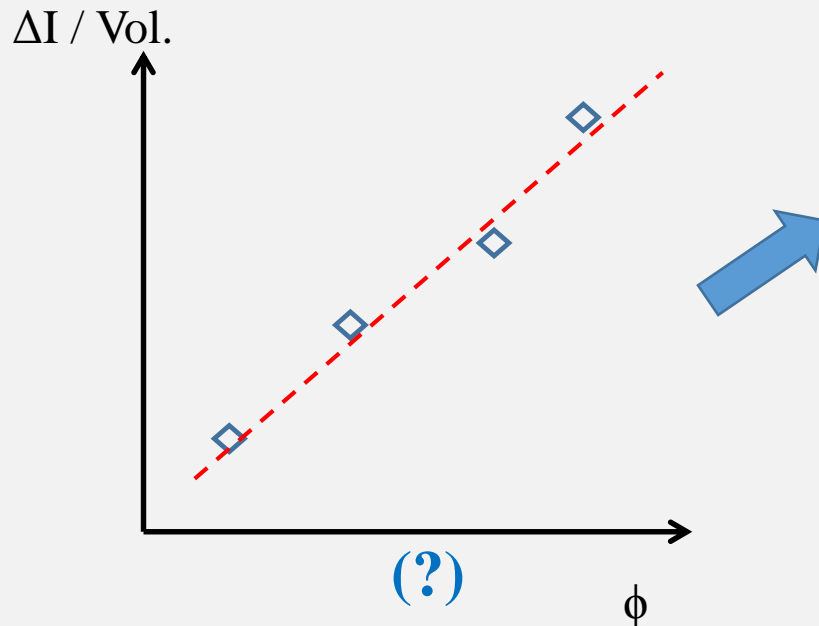
Introduction

- No previous work on NIEL measurements for heavy ions in the GeV/n energy range.
- Only analytical methods and simulations are available.



Introduction

- Attempt to use the heavy ion beams in IRRAD/CHARM to determine their hardness factors by measuring the current related damage factor α .
- Several pad diodes irradiated in different time steps and increase in leakage current measured after 80 min@60° C annealing step.



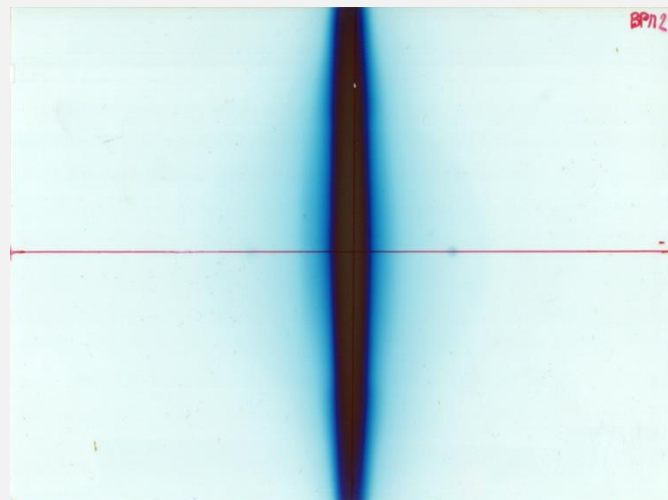
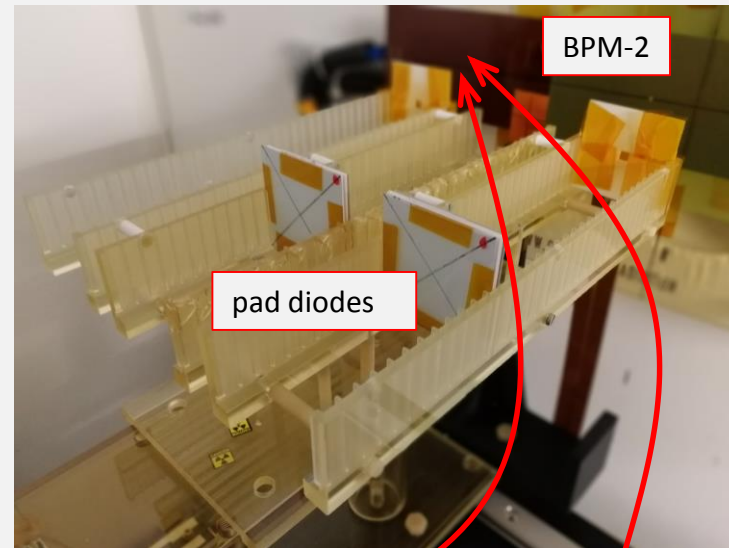
Main challenge: determining the fluence!
(no activation measured on aluminium foils...)

**Estimation based on the SEC calibration and
closest beam profile measurement**

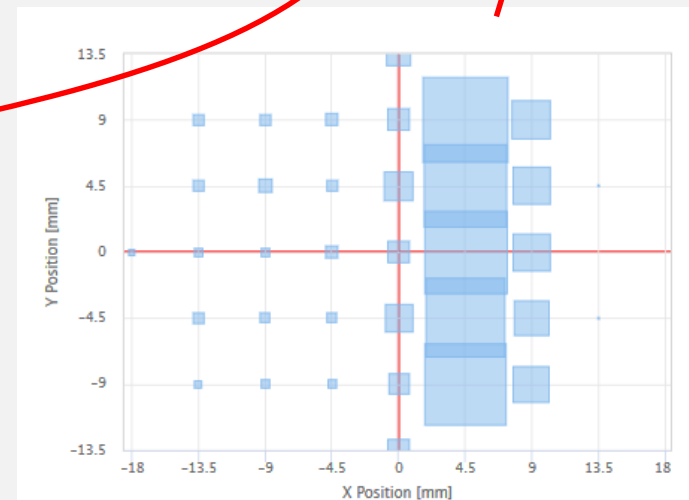
Experimental conditions

2017

- Experiment performed in IRRAD, close to BPM-2.
- 2.5x2.5 mm² active area diodes.
- Uncertainties in determining the fluence:
 - Close to beam focus on X axis (high fluence gradient, sensitive to misalignments).
 - Beam not fully contained in the BPM in the Y axis.



Gafchromic film installed on the BPM-2

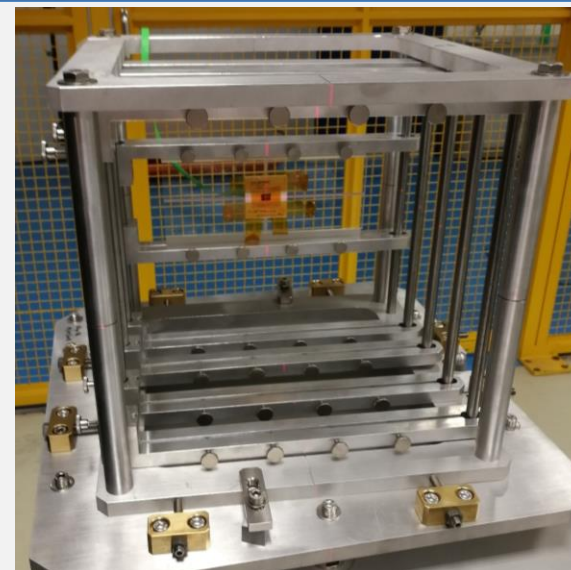


Screenshot of the BPM-2 web display.

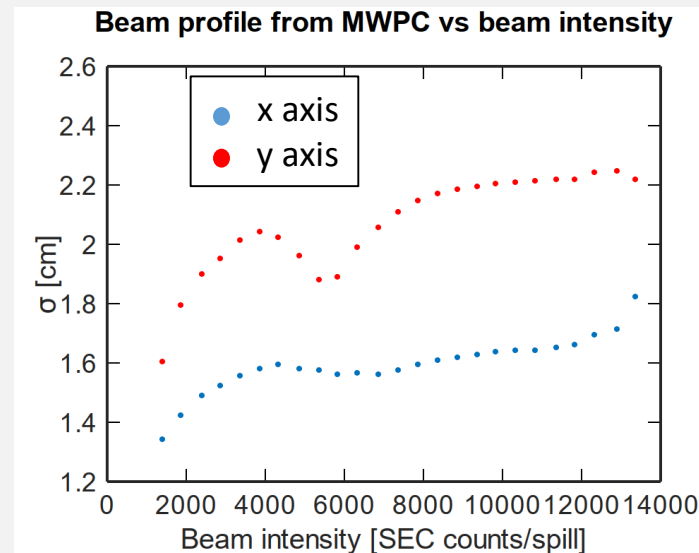
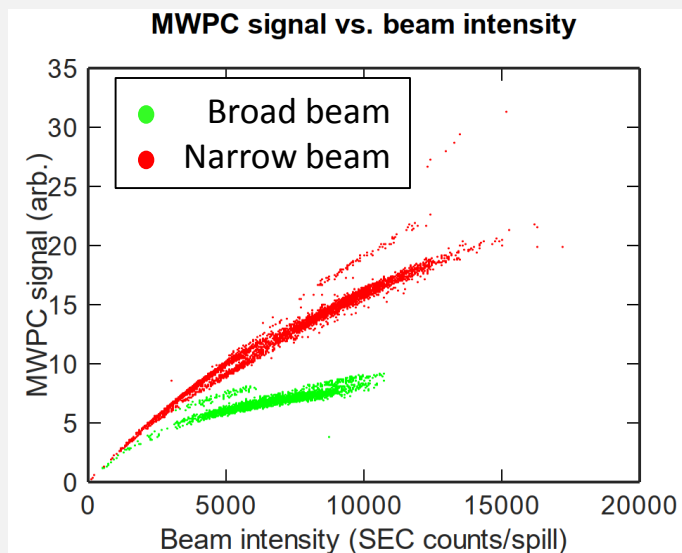
Experimental conditions

2018

- Experiment in CHARM to have a more uniform beam profile.
- 5x5 mm² active area diodes.
- Uncertainties in determining the fluence:
 - Non linear response of the MWPC induces a distortion of the measured profile.
 - Very different responses for events with similar beam intensity (under investigation).



Samples mounted on the CHARM conveyor

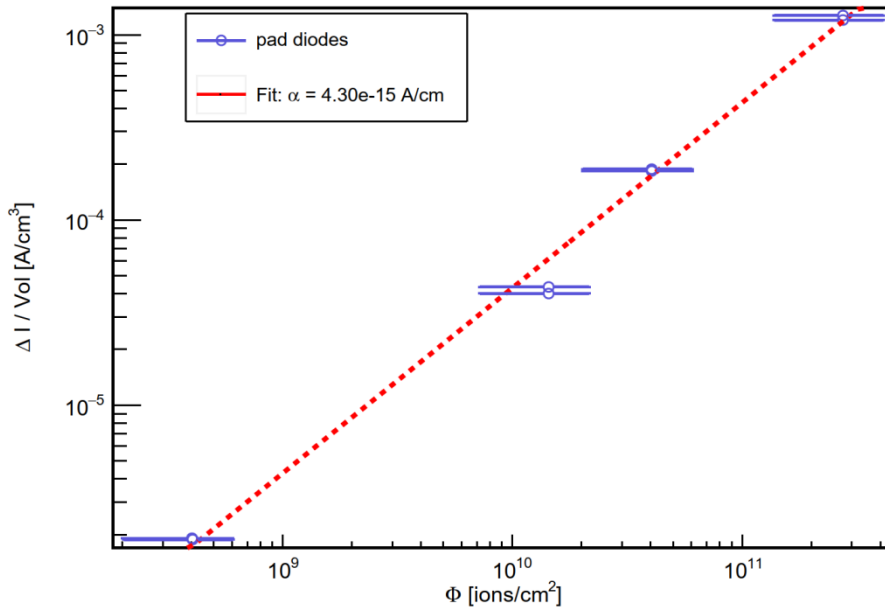


Results

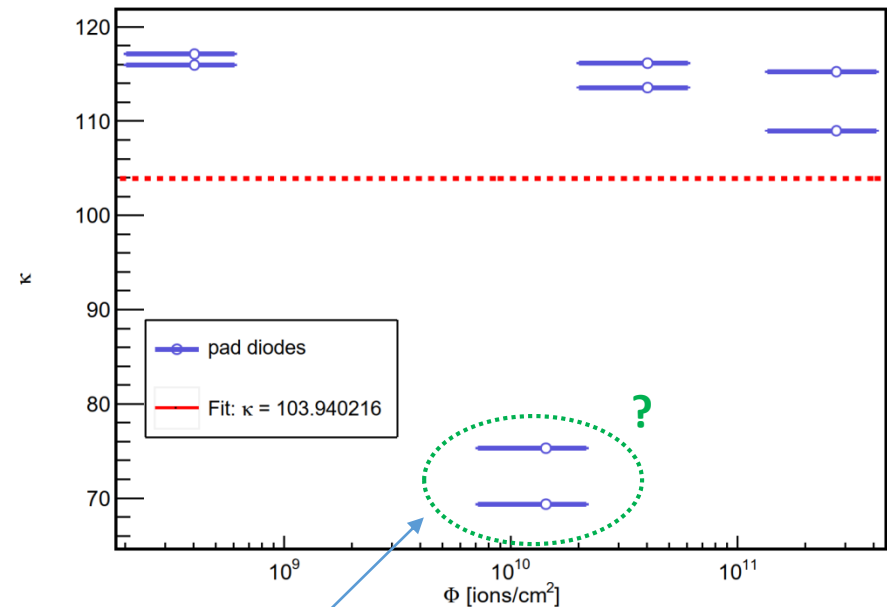
2017 - Xenon

PRELIMINARY

Leakage current scaling with fluence, 80 min@60° ann. time



Hardness factor vs. fluence, 80 min@60° ann. time



Hardness factor measured ~115 (excluding outlier)

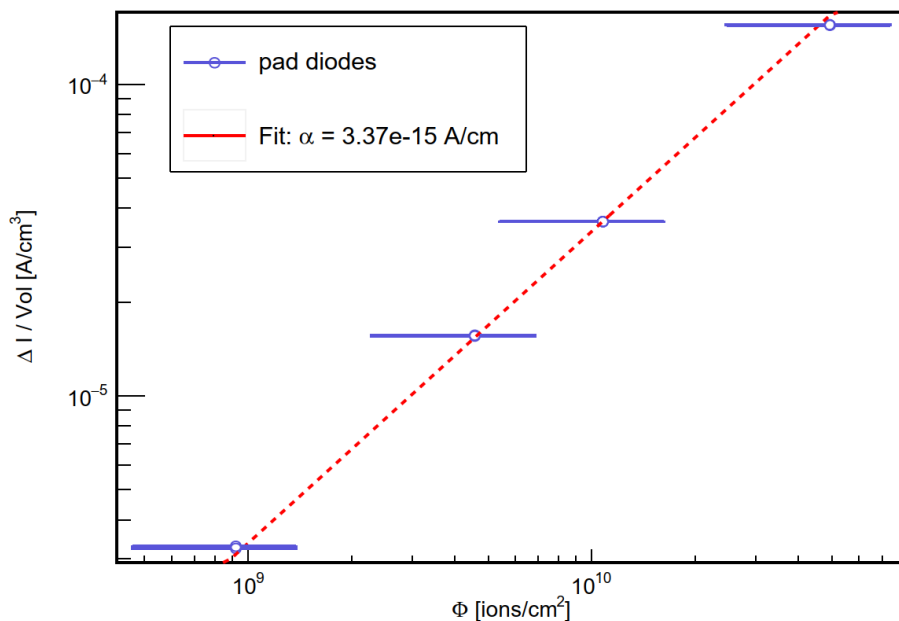
Values from FLUKA simulation and SR-NIEL are around 207!

Results

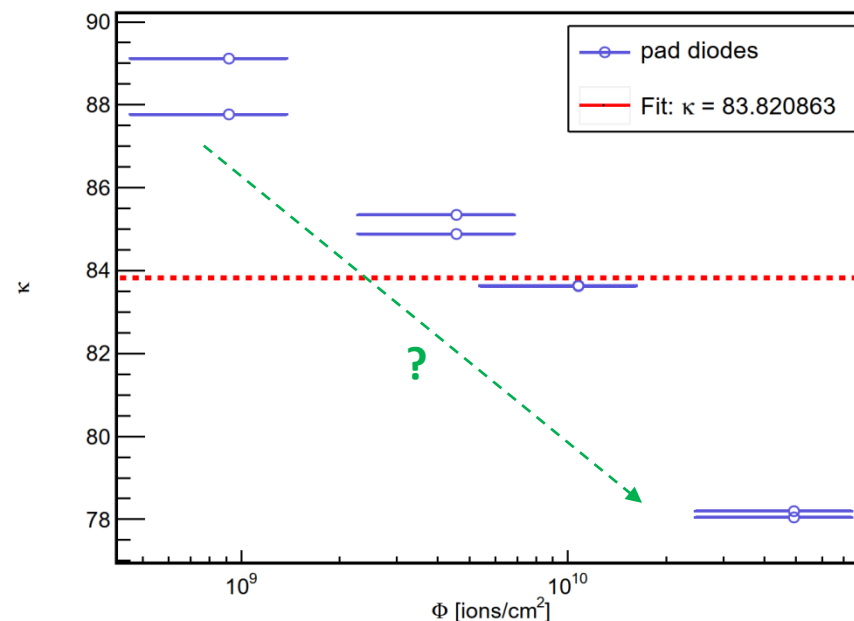
2018 - Lead

PRELIMINARY

Leakage current scaling with fluence, 80 min@60° ann. time



Hardness factor vs. fluence, 80 min@60° ann. time



Hardness factor measured ~ 84

Values from FLUKA simulation and SR-NIEL are around 400!

Summary & Outlook



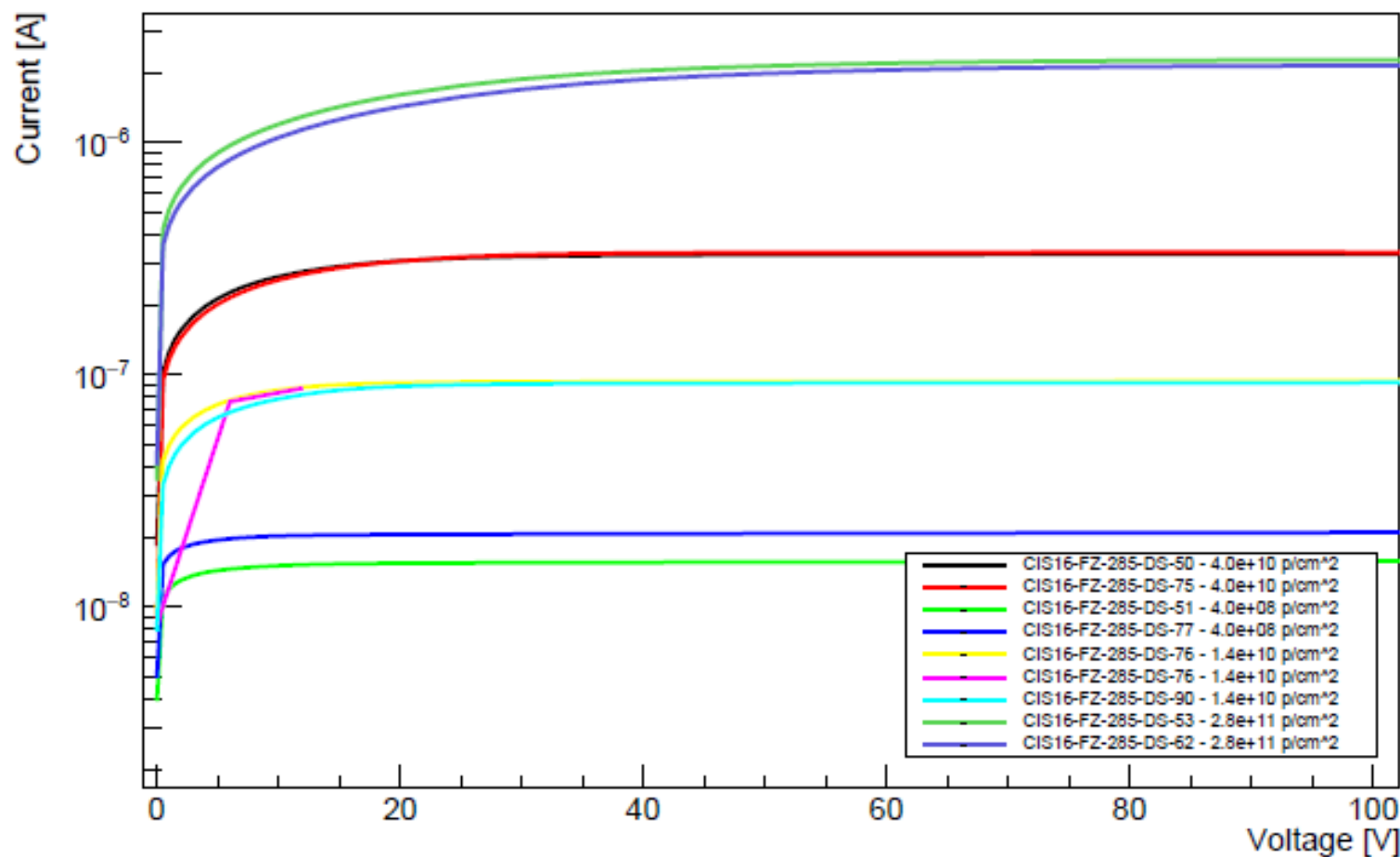
- Heavy ion runs performed in IRRAD/CHARM in 2017/18.
 - Xe 6.3 GeV/n and Pb 5.9 GeV/n.
- Experiment on NIEL in silicon performed.
 - Too many uncertainties to reliably determine the ion fluence (Mainly SEC calibration and beam profile).
 - Preliminary analysis show that measured and simulated (FLUKA) NIEL values differ largely.
 - Ion Beam dosimetry is a challenge for both the accelerator and the facility (lack of methodologies and experience).
- Outlook:
 - Get a better understanding of the beam instrumentation (verify assumptions made in present calculations).
 - Improve the data analysis for the ion fluence estimation (combine MWPC and BPM data?).
 - TSC and DLTS measurements on irradiated diodes.
- Most likely further ion runs after LS2.
 - **Potential users in the RD50 community?**
 - Potentially prepare a further experiment with improved beam diagnostics/dosimetry.

Spares

Results

2017 – I-V curves (Xenon)

IV:Irradiated, 80min annealing



Results

2018 – I-V curves (Lead)

IV:Irradiated, 80min annealing

